

Class Subclass
ISSUE CLASSIFICATION
08/160900

UTILITY
SERIAL
NUMBER 08/160000

PATENT DATE

PATENT
NUMBER

SERIAL NUMBER
08/160,909

FILING DATE
12/03/93

CLASS
135
117

SUBCLASS
84
601

GROUP ART UNIT
1107

EXAMINER
K. WILCOX

APPLICANTS
SHUNPEI YAMAZAKI, TOKYO, JAPAN; AKIRA TAKENOCHI, KANAGAWA, JAPAN;
YASUHIKO TAKEMURA, KANAGAWA, JAPAN.

CONTINUING DATA***

VERIFIED

MW

FOREIGN/PCT APPLICATIONS***

VERIFIED

JAPAN

4-350546

12/04/92

MW

Foreign priority claimed
35 USC 119 conditions met

☒ yes ☐ no
☒ yes ☐ no

AS
FILED

STATE OR
COUNTRY

SHEETS
DRWGS.

TOTAL
CLAIMS

INDEP.
CLAIMS

FILING FEE
RECEIVED

ATTORNEY'S
DOCKET NO.

Verified and Acknowledged

Examiner's Initials

JPX

5

20

3

\$710.00

0756935

ADDRESS
SIXBEY, FRIEDMAN, LEEDOM & FERGUSON
2010 CORPORATE RIDGE, SUITE 600
MCLEAN, VA 22102

TITLE
METHOD OF FABRICATING SEMICONDUCTOR DEVICES AND APPARATUS FOR
PROCESSING A SEMICONDUCTOR

U.S. DEPT. of COMM. Pat. & TM Office — PTO-436L (rev. 10-78)

PARTS OF APPLICATION
FILED SEPARATELY

Applications Examiner

NOTICE OF ALLOWANCE MAILED

CLAIMS ALLOWED

Total Claims

Print Claim

Assistant Examiner

ISSUE FEE

Amount Due

Date Paid

DRAWING

Sheets Drwg.

Figs. Drwg.

Print Fig.

Label
Area

Primary Examiner

PREPARED FOR ISSUE

ISSUE
BATCH
NUMBER

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